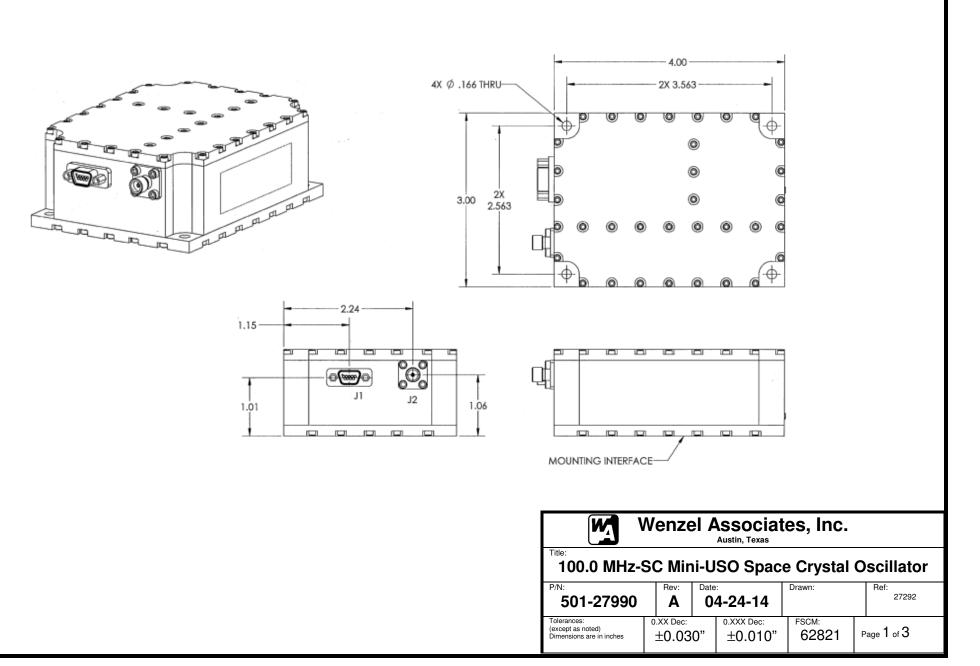
REV	DATE	REVISION RECORD	DWN	AUTH
-	04-02-14	Initial Release	Liz	
Α	04-24-14	501-	Liz	



			DEV	D. 775					DIVID	A117711
GENERAL REQUIREMENTS		1	REV	DATE			SION RECORD		DWN	AUTH
Material, Design and Construction	MIL-PRF-55310		-	04-02-14	Initial F 501-	Release			Liz Liz	
Parts and Materials List	Supplied		A	04-24-14	501-				LIZ	
Crystal Outgassing	Premium Q, Z-swept, synthetic quartz, 1/10 output frequency TML<1% and CVCM <0.1% per SP-R-002A									
Traceability	Semiconductor and passive lot and date code tracking									
De-rating	per EEE-INST-002, (JPL-D-8545, alternative)									
Soldering	J-STD-001 class 3	MODEL D	EFINITI	ONS						
Case Finish	Nickel-plated aluminum housing Electroless nickel per MIL-C-26074	_								
1 111511	Liectioless flicker per Mil-0-20074	PF (Proto	-Flight	Model)			uction similar in			
F					form, f	fit, and function	on to FM. Deve some commerc	loped using b	pest com	mercial
ELECTRICAL PERFORMANCE							only to electrica			5. EIVI
RF Output Frequency	100 MHz (fixed, please specify), sine wave						ing performed.			
Frequency Accuracy (initial)	$\pm 1 \times 10^{-8}$ at $\pm 25^{\circ}$ C									
Frequency Stability Aging Rate (after 90 days operating)	$<1x 10^{-9}$ over 3°C, -20°C to +60°C, under vacuum	FM (Flight Model)		Fabricated to meet all design, construction, and test requirements reference MIL-PRF-55310, Class 1, Product level						
1 day	$\pm 2 \times 10^{-10}$						jected to the en		ent of ele	ctrical
1 year	±2 x 10 <sup>-o</sup> after 60 days operating				and er	nvironmental	acceptance tes	sts listed.		
RF Output Power	+12 dBm $\pm 2$ dB into 50 $\Omega$				Fliaht	Model Space	e Level, Parts E	EE-INST-002	2. Level 1	.2.3
RF Output 2 <sup>nd</sup> Harmonic	-30 dBc						el 2 Crystals, T			
RF Output Sub-harmonics RF Output Spurious	≤-40 dBc ≤-100 dBc, 100 KHz to 1 GHz				by sim					
Phase Noise (Static)	100 MHz				MIL-PRF-19500 / MIL-STD-750 Semiconductors, JANTXV with PIN D, JANTX with PIN D and DPA (5 ea)					
10 Hz	-116 dBc/Hz				JANT		D, JAN I X with I	PIN D and DF	PA (5 ea	)
100 Hz	-134 dBc/Hz	Qualificati	on Moc	hel	FM un	nit, when spe	cified, using EE	F-INST-002	l evel 1	2.3 parts
1kHz	-141 dBc/Hz	Quantoat	0		where	available. Te	esting for (1) un	nit.	,	_,0 puito
10kHz 100kHz	-142 dBc/Hz -142 dBc/Hz						0 ()			
Allen Deviation (10 to 10kHz)	1 second 3e-12									
	10 seconds 3e-12									
	100 seconds 3e-12	501-279	90-01		Proto-	Flight Model	I			
Supply voltage	+15 VDC ±5%	504 070								
Warm-up power	≤8 watts ≤20 minutes at ambient pressure ≤5 x $10^{-5}$ torr	501-279	90-02	2	Qualiti	ication Mode	1			
Warm-up time	·	501.070		<b>,</b>						
Input power	≤5 watts steady state at ambient pressure ≤5 x 10 <sup>-5</sup> torr	501-279	90-03	5	FM FI	ight Model				
<b>ENVIRONMENTAL CONDITIONS</b>										
Acceptance temperature	-20°C to +60°C									
Proto-flight temperature	$-20^{\circ}$ C to $+60^{\circ}$ C									
Storage temperature	-40°C to +85°C									
Ambient pressure	Atmospheric (760 torr), Vacuum (≤5 x 10 <sup>-5</sup> torr)									
MECHANICAL SPECIFICATIONS										
Size	4" x 3" x 1.5"									
Weight	≤380 grams									
Physical	Pressure relief holes, vented				١٨/	onzol A	oconiat	a Ina		
					VV		Austin, Texas	5, IIIC.		
		Title: 100.0 MHz-SC Mini-USO Space Crystal Osci								
						llator				
			P/N			Rev: Date		Drawn:	Ref:	
				501-279	990		4-02-14			27292
			Tole	rances:	0	).XX Dec:	0.XXX Dec:	FSCM:		
I Contraction of the second			(exc	ept as noted) ensions are in inche		±0.030"	±0.010"	62821	Page 2	2 of 3
I Contraction of the second		1				_0.000	_0.0.0			

### QUALIFICATION TESTS (Non-flight model, only)

	ao, o,
Group I (1 samples)	Visual, Electrical Tests*
Burn-In (operational)	240 hours minimum at +75°C
Group II (1 samples)	
Aging	30 Days
Group III Subgroup 1 (1 sample)	
Random Vibration	11.95 Grms, MIL-STD-202, method 214 I-D,
	50 to 2000 Hz, 5 min per axis
Shock	MIL-STD-202, Method 213, Condition A, 50G, 11msec
Group III Subgroup 2 (1 sample)	
Thermal Shock	MIL-STD-202, Method 107, Condition A-1,
	25 cycles, -55°C to +85°C

Ambient Pressure Group III Subgroup 3 (1 sample) Resistance to Soldering Heat Group III Subgroup 4 (1 sample) Terminal Strength

Solderability Resistance to Solvents

Electrical Tests\* Radiographics

## ACCEPTANCE TESTS (Flight Model)

Electrical Tests\* Random Vibration (non-operational) 7.56 Grms overall, MIL-STD-202 Method 214 Test Cond I-B,

Thermal Shock

Electrical Tests\* Burn-In (operational) Aging Rate Electrical Tests\* Radiographics 5 Cycles, -55°C to +85°C 240 hours minimum at +75°C Projected to 30 days operating

MIL-STD-202, Method 107, Condition A.

MIL-STD-202. Method 105. at  $<5 \times 10^{-5}$  torr

MIL-STD-202, Method 210, Condition A

MIL-STD-202, Method 211, Condition C,

Not applicable when marking is electro-etched

Not applicable for pins <0.25"

MIL-STD-202, Method 208 MIL-STD-202, Method 215

MIL-STD-202, method 209

50 to 2000 Hz. 5 min per axis

MIL-STD-202, method 209

### \*ELECTRICAL TESTS

Tested at ambient pressure  $\leq 5 \times 10^{-5}$  torr and at -20, +25, and 60 °C unless otherwise noted

Warm-Up Power (-20  $^{\circ}$ C only) Warm-Up Time (-20  $^{\circ}$ C only) Input Power Cold Start (-20  $^{\circ}$ C) Hot Start (+60  $^{\circ}$ C) RF Output Power RF Output Harmonics RF Output Harmonics RF Output Spurious Frequency Accuracy (+25  $^{\circ}$ C only) Frequency Stability Phase Noise - Static (+25  $^{\circ}$ C only, 760 torr)

# ANALYSES

Thermal Analysis, Component Stress Analysis

REV	DATE	REVISION RECORD	DWN	AUTH
-	04-02-14	Initial Release	Liz	
Α	04-24-14	501-	Liz	

# Wenzel Associates, Inc. Title: 100.0 MHz-SC Mini-USO Space Crystal Oscillator P/N: Rev: Date: Drawn: Ref: 27292

501-27990	Α	0	4-02-14		21232
Tolerances: (except as noted) Dimensions are in inches	0.XX Dec: ±0.03	0"	0.XXX Dec: ±0.010"	FSCM: 62821	Page 3 of 3